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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Lindsey H. Hall, et al.

Docket No: TI-35168

Serial No: 10/825,351

Conf. No: 8635

Examiner: Steven J. Fulk

Art Unit: 2891

Filed: 04/15/2004

For: RECESS REDUCTION FOR LEAKAGE IMPROVEMENT IN HIGH DENSITY
CAPACITORS

ELECTION

Commissioner For Patents
P.O. Box 1450
Alexandria, VA 22313-1450

MAILING CERTIFICATE UNDER 37 C.F.R. § 1.8(a)

I hereby certify that the above correspondence is being deposited with the U.S. Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on 7-8-05.

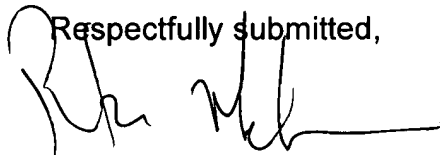

Ann Trent

Dear Sir:

This election is offered in response to the Examiner's restriction requirement mailed June 21, 2005.

Applicants hereby elect to pursue Group II of Claims 1-10 and 16-20, drawn to a method of reducing recess relief within an interconnect structure and a method of fabricating an integrated circuit, without traversing the Examiner's restriction requirement.

Respectfully submitted,



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